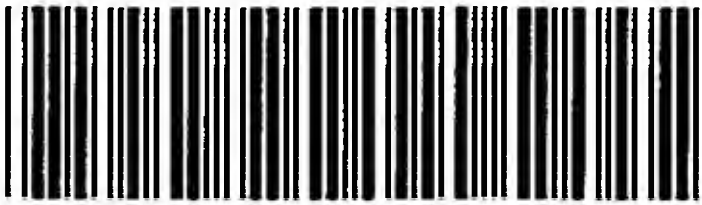


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,502	LO ET AL.	
	Examiner	Art Unit	
	Sun J. Lin	2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	5	5/10/2006	JSL
716	4	5/10/2006	JSL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	5	5/10/2006	JSL
716	4	5/10/2006	JSL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	5/10/2006	JSL